

**Search Notes**

Application/Control No.

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Examiner

Richard H. Kim

Applicant(s)/Patent under  
Reexamination

KANO ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Text Seach (349/114,113)- epo,jpo,uspat,pgpub-see printout	10/2/2005	RHK